

			02.11.2011
RefMat No 38 Category 1 Critical Dimensions Category 2 Lateral (X-Y-axis, 1-dim) Comar Database: Green 1> YES Blue 0> NO Type_of_RefMat: Name of RM: NanoLattice (TM) (NLSM) 100 nm pitch standard Description Surface Topography Standards (STS), gratings with near perfect periodicity combination of step height and pitch			
Link http://www.vlsistandards.com/products/dimensional/ststandards.asp?sid=47			
Certified Qantities			
	step height	MeanValue	18 nm Uncertainty
	step height	MeanValue	44 nm Uncertainty
	lateral distance	MeanValue	100 nm Uncertainty
	lateral distance	MeanValue	180 nm Uncertainty
ļ		MeanValue	nm Uncertainty
Calibration of Calibration of Calibration of Calibration of Calibration of	AFM SEM Interferometer WLIM		Characterised by Characterised by Characterised by Characterised by Characterised by Characterised by
2 Provider No 3			
Provider No		://www.vlsistanda	rds.com
Provider	VLSI Standards, Inc.		
Contact Person	Marc Helvey, ext. 108	Country City	USA San Jose
Email	sales.support@visistd.com	City Code	CA 95134-2006
Phone	(408) 428-1800	Street + No	3087 North First Street
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